Electron Radiation Damage of Pentacene Thin Films Measured in TEM

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We have investigated the mechanism of radiation damage (RD) in pentacene thin films by diffraction ring fading (loss of crystallinity). Pentacene has application in large area flexible organic electronics [1]. Pentacene films can be studied by TEM if artifacts from RD are avoided.

We have grown 70nm thick pentacene films onto carbon coated TEM grids by sublimation from a Knudsen cell. The samples were characterized in a JEOL 2010 at 200 kV. The intensity of each diffraction ring was integrated over all azimuthal angles. The integrated diffraction intensity (IDI) fitted to a Lorentzian was plotted as a function of electron dose. Fig. 1 shows the typical initial film (lower left) and a damaged film (upper right) and corresponding diffraction patterns while Fig. 2 shows dependence of IDI on radiation dose for a sample at room temperature (RT) and 90 K. The characteristic doses $D_{1/e}$ estimated from the region of Fig. 2 where IDI for a given reflection decreases (excluding the latent dose where little change of IDI takes place) are given in Table 1.

Measured $D_{1/e}$ were compared to calculated $D = e^{1/2}$; here e is electron charge and the cross section

was calculated for carbon 1s using the SIGMAK3 program [2]. The for valence electrons (including hydrogen 1s shell) was calculated from measured plasmon energy $E_p = 23.6 \text{ eV}$ and width of the plasmon resonance $E_p = 16.7 \text{ eV}$ using

$$\sigma_{tot}^{val} = \frac{1}{\pi a_0 m_0 v^2 n_a} \int_0^{E_0} \left(\ln \left[\theta_E^2 + 2 \theta_E \right] - \ln \left[\theta_E^2 \right] \right) \Im \left(-\frac{1}{\epsilon(E)} \right) dE$$

where the imaginary part of dielectric function (E) is

 $\Im\left(-\frac{1}{\epsilon(E)}\right) = \frac{E\Delta E_p E_p^2}{(E^2 + E_p^2)^2 + (E\Delta E_p)^2}$

 a_0 is Bohr radius, E_0 incident energy, m_0 electron mass, v electron velocity and n_a is number of atoms per unit volume. These calculated doses $D_{1/e}$ per atom were converted to $D_{1/e}$ per molecule by multiplying by the number of atoms (22 for C 1s, 36 for valence shells) [3]. IDI for higher-index rings in Fig. 2 show a monotonic decay with dose but lower- index rings either stay unchanged or become more intense before decaying. This might be explained by considering two competing mechanisms: the decrease of IDI due to damage of the crystal structure and a mechanism of IDI increase (such as change of crystallite orientation closer to Bragg condition). It should be noted that $D_{1/e}$ (Table 2) for the valence excitations is too low to explain the measured $D_{1/e}$ (Table 1) unless there is an efficient healing mechanism repairing about up to 45% of bond at RT and about 99 % of bond at 90 K. $D_{1/e}$ at 90K corresponds well to $D_{1/e}$ for a single carbon-1s excitation per molecule, suggesting (but not proving) that the damage mechanism is related to carbon 1s excitation [4].

References

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Figure 1 a) Pentacene film. Damaged area in upper right, pristine film in lower left.



Figure 2a) Diffraction intensity as function of dose at 90K.

TABLE 1	Measu	red dan	nage	doses.

Temp.	Dose rate	e Miller Latent dose		Char.dose	Critical
- •p	j	index	D _L	D _{1/e}	dose
					D_{c}
	$[A/cm^2]$		$[C/cm^2]$	$[C/cm^2]$	$[C/cm^{2}]$
	0.6x10 ⁻³	110	0.18	0.1	0.45
		200	0.18	0.06	0.45
205V		210	0.18	0.03	0.45
293K		220	< 0.03	0.07	0.14
		130	< 0.03	0.11	0.14
		230	< 0.03	0.07	0.14
	4.3x10 ⁻³	110	1.1	0.5	2.4
		200	~1	0.4	2.4
OOV		210	0.7	0.5	2.4
90 K		220	NA	0.3	1.2
		130	< 0.3	0.6	1.2
		230	< 0.1	0.85	1.2



Figure 1b) Diffraction patterns from damaged (above) and pristine area (below).



Figure 2b) Diffraction intensity as function of dose at 295 K.

TABLE 2	2 Calcul	lated	damage	e doses.

	U			
C 1s	valence	C1s	valence	
$D_{1/e}$	elect. D _{1/e}	D _{1/e}	elect. D _{1/e}	
1/atom	1/atom	1/molec.	1/molec	
$[C/cm^2]$	$[C/cm^2]$	$[C/cm^2]$	$[C/cm^2]$	
10	0.06	0.47	1.5×10^{-3}	

